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X-Ray Nanoimaging: Instruments and Methods III

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Andrea Somogyi
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Contents

v	<i>Authors</i>
vii	<i>Conference Committee</i>

OPTICS

10389 09	Focus of a multilayer Laue lens with an aperture of 102 microns determined by ptychography at beamline 1-BM at the Advanced Photon Source [10389-8]
----------	--

NANO-IMAGING/CORRELATIVE METHODS

10389 0D	Simulations and experiments on vibration damping for zoom-holography and nano-scanning at the GINIX [10389-12]
10389 0E	PtyNAMI: ptychographic nano-analytical microscope at PETRA III: interferometrically tracking positions for 3D x-ray scanning microscopy using a ball-lens retroreflector [10389-13]
10389 0F	High-energy cryo x-ray nano-imaging at the ID16A beamline of ESRF (Invited Paper) [10389-14]

SCANNING NANOPROBES

10389 0J	Current status of the hard x-ray nanoprobe beamline at the SSRF (Invited Paper) [10389-19]
10389 0K	First x-ray nanoimaging experiments at NanoMAX [10389-20]

POSTER SESSION

10389 0T	Faster scanning and higher resolution: new setup for multilayer zone plate imaging [10389-29]
10389 0U	PyXRF: Python-based x-ray fluorescence analysis package [10389-30]
10389 14	Arsenic distribution and valence state variation studied by fast hierarchical length-scale morphological, compositional, and speciation imaging at the Nanoscopium, Synchrotron Soleil [10389-41]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Baranton, Gil, 14	Somogyi, Andrea, 14
Björling, Alexander, 0K	Sprung, Michael, 0D
Bloch, Leonid, 0F	Stankevič, Tomaš, 0K
Bohic, Sylvain, 0F	Visscher, P. T., 14
Botta, Stephan, 0E	Vogt, Ulrich, 0K
Bouet, Nathalie, 09	Wang, Hua, 0J
Campbell, Stuart I., 0U	Wittwer, Felix, 0E
Carbone, Gerardina, 0K	Wojcik, Michael, 09
Chu, Yong S., 0U	Xu, Wei, 0U
Cloetens, Peter, 0F	Yan, Hanfei, 0U
Conley, Raymond, 09	Yang, Yang, 0F
da Silva, Julio C., 0F	Yu, Dantong, 0U
Döhrmann, Ralph, 0E	Zhang, Zhaohong, 0J
Eberl, Christian, 0T	Zhao, Gaofeng, 0J
Falkenberg, Gerald, 0E	
Fus, Florin, 0F	
Garrevoet, Jan, 0E	
He, Yan, 0J	
Heroux, Annie, 0U	
Hubert, Maxime, 0F	
Jiang, Hui, 0J	
Johansson, Ulf, 0K	
Kahnt, Maik, 0E	
Kalbfleisch, Sebastian, 0K	
Krebs, Hans-Ulrich, 0T	
Lee, Wah-Keat, 0U	
Li, Aiguo, 0J	
Li, Li, 0U	
Liebi, Marianne, 0K	
Luley, Peter, 0D	
Lyubomirskiy, Mikhail, 0E	
Macrander, Albert, 09	
Maser, Jörg, 09	
Matej, Zdenek, 0K	
Medjoubi, Kadda, 14	
Mikkelsen, Anders, 0K	
Osterhoff, Markus, 0D, 0T	
Pacureanu, Alexandra, 0F	
Parfeniukas, Karolis, 0K	
Philippot, Pascal, 14	
Salditt, Tim, 0D	
Salome, Murielle, 0F	
Sancho-Tomas, Maria, 14	
Scholz, Maria, 0E	
Schroer, Christian G., 0E	
Schropp, Andreas, 0E	
Seyrich, Martin, 0E	
Shu, Deming, 0J	
Soltau, Jakob, 0T	

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- 5 Scanning Nanoprobes
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